MOTOROLA SEMICONDUCTOR TECHNICAL DATA

32K x 9 Bit BurstRAM™ Synchronous Static RAM With Burst Counter and Self-Timed Write

The MCM62940A is a 294,912 bit synchronous static random access memory designed to provide a burstable, high-performance, secondary cache for the MC68040 and PowerPC™ microprocessors. It is organized as 32,768 words of 9 bits, fabricated using Motorola's high-performance silicon-gate CMOS technology. The device integrates input registers, a 2-bit counter, high speed SRAM, and high drive capability outputs onto a single monolithic circuit for reduced parts count implementation of cache data RAM applications. Synchronous design allows precise cycle control with the use of an external clock (K). CMOS circuitry reduces the overall power consumption of the integrated functions for greater reliability.

Addresses (A0 – A14), data inputs (DQ0 – DQ8), and all control signals, except output enable (\overline{G}) , are clock (K) controlled through positive-edge-triggered noninverting registers.

Bursts can be initiated with either transfer start processor (TSP) or transfer start cache controller (TSC) input pins. Subsequent burst addresses are generated internally by the MCM62940A (burst sequence imitates that of the MC68040) and controlled by the burst address advance (BAA) input pin. The following pages provide more detailed information on burst controls.

Write cycles are internally self-timed and are initiated by the rising edge of the clock (K) input. This feature eliminates complex off-chip write pulse generation and provides increased flexibility for incoming signals.

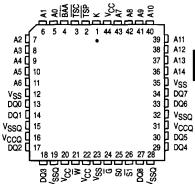
The MCM62940A is packaged in a 44-pin plastic-leaded chip carrier (PLCC). Multiple power and ground pins have been utilized to minimize effects induced by output noise. Separate power and ground pins have been employed for DQ0 – DQ8 to allow user-controlled output levels of 5 volts or 3.3 volts.

- Single 5 V ± 10% Power Supply
- Choice of 5 V or 3.3 V ± 10% Power Supplies for Output Level Compatibility
- Fast Access Times: 11/12/14/19/24 ns Max, Cycle Times: 15/20/20/25/30 ns Min
- · Internal Input Registers (Address, Data, Control)
- · Internally Self-Timed Write Cycle
- TSP, TSC, and BAA Burst Control Pins
- Asynchronous Output Enable Controlled Three-State Outputs
- · Common Data Inputs and Data Outputs
- . High Output Drive Capability: 85 pF per I/O
- · High Board Density PLCC Package
- Fully TTL-Compatible
- Active High and Low Chip Select Inputs for Easy Depth Expansion

MCM62940A



PIN ASSIGNMENT

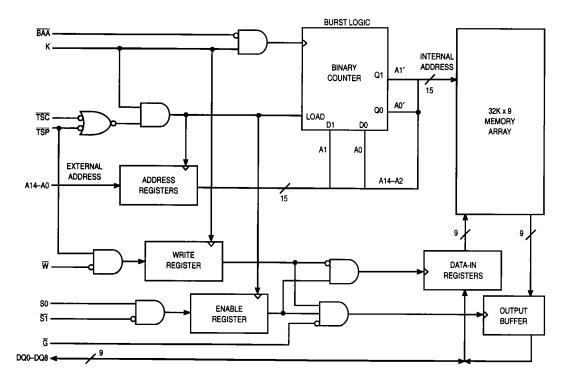


PIN NAMES
A0 - A14 Address inputs
K Clock
W Synchronous Write
G Output Enable
S0, \$1 Chip Selects
BAA Burst Address Advance
TSP, TSC Transfer Start
DQ0 - DQ8 Data input/Output
V _{CC} + 5 V Power Supply
VCCO Output Buffer Power Supply
Vss Ground
VSSQ Output Buffer Ground

All power supply and ground pins must be connected for proper operation of the device. V_{CC}≥V_{CCQ} at all times including power up.

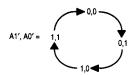
BurstRAM is a trademark of Motorola, Inc. PowerPC is a trademark of IBM Corp.

BLOCK DIAGRAM (See Note)



NOTE: All registers are positive-edge triggered. The TSC or TSP signals control the duration of the burst and the start of the next burst. When TSP is sampled low, any ongoing burst is interrupted and a read (independent of W and TSC) is performed using the new external address. When TSC is sampled low (and TSP is sampled high), any ongoing burst is interrupted and a read or write (dependent on W) is performed using the next external address. Chip selects (S0, ST) are sampled only when a new base address is loaded. After the first cycle of the burst, BAA controls subsequent burst cycles. When BAA is sampled low, the internal address is advanced prior to the operation. When BAA is sampled high, the internal address is not advanced, thus inserting a wait state into the burst sequence accesses. Upon completion of a burst, the address will wrap around to its initial state. See BURST SEQUENCE GRAPH.

BURST SEQUENCE GRAPH (See Note)



NOTE: The external two values for A1 and A0 provide the starting point for the burst sequence graph. The burst logic advances A1 and A0 as shown above.

SYNCHRONOUS TRUTH TABLE (See Notes 1, 2, 3, and 4)

s	TSP	TSC	BAA	W	K	Address	Operation
F	٦	X	Х	Х	L-H	N/A	Deselected
F	X	L	х	х	L-H	N/A	Deselected
Т	٦	X	X	х	L-H	External Address	Read Cycle, Begin Burst
Т	I	L	X	L	L-H	External Address	Write Cycle, Begin Burst
Т	I	L	x	Н	L-H	External Address	Read Cycle, Begin Burst
Х	Ή	Н	L	L	L-H	Next Address	Write Cycle, Continue Burst
×	Н	Н	L	н	L-H	Next Address	Read Cycle, Continue Burst
×	Н	Н	н	L	L-H	Current Address	Write Cycle, Suspend Burst
Х	Ξ	Н	Н	Н	L-H	Current Address	Read Cycle, Suspend Burst

NOTES:

- 1. X means Don't Care.
- 2. All inputs except \overline{G} must meet setup and hold times for the low-to-high transition of clock (K).
- 3. S represents S0 and $\overline{S1}$. T implies S0 = H and $\overline{S1}$ = L; F implies S0 = L or $\overline{S1}$ = H.
- 4. Wait states are inserted by suspending burst.

ASYNCHRONOUS TRUTH TABLE (See Notes 1 and 2)

	,	· · · · · · · · · · · · · · · · · · ·
Operation	G	I/O Status
Read	L	Data Out (DQ0-DQ8)
Read	н	High-Z
Write	x	High-Z — Data In (DQ0-DQ8)
Deselected	Х	High-Z

NOTES:

- 1. X means Don't Care.
- For a write operation following a read operation, G must be high before the input data requird setup time and held high throughout the input data hold time.

ABSOLUTE MAXIMUM RATINGS (Voltages referenced to VSS = 0)

Rating	Symbol	Value	Unit
Power Supply Voltage	Vcc	- 0.5 to 7.0	٧
Output Power Supply Voltage	VccQ	- 0.5 to V _{CC}	V
Voltage Relative to V _{SS}	V _{in} , V _{out}	- 0.5 to V _{CC} + 0.5	٧
Output Current (per I/O)	lout	± 20	mA
Power Dissipation	PD	1.0	w
Temperature Under Bias	T _{bias}	- 10 to + 85	°C
Operating Temperature	TA	0 to + 70	°C
Storage Temperature	Tstg	- 55 to + 125	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPER-ATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.

This CMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established.

DC OPERATING CONDITIONS AND CHARACTERISTICS

(V_{CC} = 5.0 V \pm 10%, V_{CCQ} = 5.0 V or 3.3 V \pm 10%, T_A = 0 to + 70°C, Unless Otherwise Noted)

RECOMMENDED OPERATING CONDITIONS (Voltages referenced to VSS = 0 V)

Parameter	Symbol	Min	Тур	Max	Unit						
Supply Voltage (Operating Voltage Range)	Vcc	4.5	5.0	5.5	٧						
Output Buffer Supply Voltage (5.0 V TTL Compatible) (3.3 V 50 Ω Compatible)	Vccq	4.5 3.0	5.0 3.3	5.5 3.6	V						
Input High Voltage	V _{IH}	2.2	_	V _{CC} + 0.3	V						
Input Low Voltage	VIL	- 0.5*		0.8	٧						

^{*}V_{IL} (min) = -3.0 V ac (pulse width ≤ 20 ns)

DC CHARACTERISTICS

Parameter	Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, V _{in} = 0 to V _{CC})	llkg(l)	_	± 1.0	μА
Output Leakage Current $(\overline{G}, \overline{S1} = V_{IH}, S0 = V_{IL}, V_{out} = 0 \text{ to } V_{CCQ})$	llkg(O)	_	± 1.0	μА
AC Supply Current (G, S1 = V _{IL} , S0 = V _{IH} , All Inputs = V _{IL} = 0 V and V _{IH} ≥ 3.0 V, I _{Out} = 0 mA, Cycle Time ≥ t _{KHKH} min)	ICCA	_	165	mA
Standby Current (S1 = V _{IH} , S0 = V _{IL} , All Inputs = V _{IL} and V _{IH} , Cycle Time ≥ t _{KHKH} min)	SB1		40	mA
CMOS Standby Current $(\overline{S1} \ge V_{CC} - 0.2 \text{ V}, S0 \le 0.2 \text{ V}, All Inputs \ge V_{CC} - 0.2 \text{ V} \text{ or } \le 0.2 \text{ V}, Cycle Time \ge t_{KHKH} min)$	ISB2	_	30	mA
Output Low Voltage (I _{OL} = + 8.0 mA)	V _{OL}	_	0.4	V
Output High Voltage (I _{OH} = - 4.0 mA)	Voн	2.4		٧

NOTE: Good decoupling of the local power supply should always be used. DC characteristics are guaranteed for all possible MC68040 bus cycles.

$\textbf{CAPACITANCE} \text{ (f = 1.0 MHz, dV = 3.0 V, T}_{\c A} = 25^{\circ}\text{C, Periodically Sampled Rather Than 100\% Tested)}$

Characteristic	Symbol	Тур	Max	Unit
Input Capacitance (All Pins Except DQ0 - DQ8)	C _{in}	2	3	ρF
Input/Output Capacitance (DQ0 - DQ8)	C _{I/O}	7	8	pF

AC OPERATING CONDITIONS AND CHARACTERISTICS

(V_{CC} = 5.0 V \pm 10%, V_{CCQ} = 5.0 V or 3.3 V \pm 10%, T_A = 0 to + 70°C, Unless Otherwise Noted)

Input Timing Measurement Reference Level 1.5 V	Output Timing Reference Level 1.5 V
Input Pulse Levels	Output Load See Figure 1A Unless Otherwise Noted
Input Rise/Fall Time	

READ/WRITE CYCLE TIMING (See Notes 1, 2, and 3)

	Sym	Symbol 62940		2940A-11 62940A-12		62940A-14 62940		62940A-19 62940A-24)A-24				
Parameter	Std	Alt	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Cycle Time	tKHKH	tcyc	15	_	20		20	_	25	_	30	_	ns	
Clock Access Time	t _K HQV	tCD		11	_	12	-	14	_	19	_	24	ns	4
Output Enable to Output Valid	[†] GLQV	^t OE	_	5	_	5	_	6	-	7		7	ns	
Clock High to Output Active	tKHQX1	^t DC1	6	_	6	_	6	_	6	_	6	_	ns	
Clock High to Output Change	tKHQX2	tDC2	3	_	3	_	5	_	5	-	5	_	ns	
Output Enable to Output Active	^t GLQX	tolz	0	_	0	_	0		0	_	0	-	ns	
Output Disable to Q High-Z	†GHQZ	^t OHZ	_	6		6	_	6	_	7	_	7	ns	5
Clock High to Q High-Z	tKHQZ	tcz	_	6	_	6	_	6	_	6	_	6	ns	5
Clock High Pulse Width	†KHKL	t _{CH}	5.5	_	7	_	8	_	9	_	11	_	ns	
Clock Low Pulse Width	^t KLKH	^t CL	5.5	_	7	_	8	_	9	_	11	_	ns	
Setup Times: Address Address Status Data In Write Address Advance Chip Select	tavkh ttsvkh tdvkh twvkh tbavkh tsovkh ts1vkh	tas tss tds tws	2	_	2	_	3	_	3	-	3	_	ns	6
Hold Times: Address Address Status Data In Write Address Advance Chip Select	tKHAX tKHTSX tKHDX tKHWX tKHBAX tKHSOX tKHSOX	tah tsh tdh twh	2	_	2	_	2		2	_	2		ns	6

NOTES:

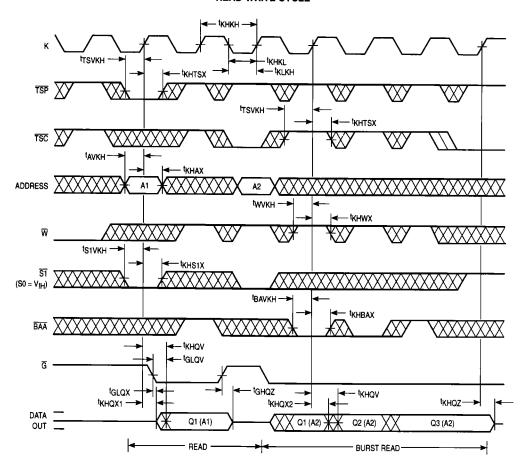
- 1. A read cycle is defined by \overline{W} high or \overline{TSP} low for the setup and hold times. A write cycle is defined by \overline{W} low and \overline{TSP} high for the setup and hold times.
- 2. All read and write cycle timings are referenced from K or G.
- 3. \overline{G} is a don't care when \overline{W} is sampled low.
- 4. Maximum access times are guaranteed for all possible MC68040 external bus cycles.
- 5. Transition is measured ± 500 mV from steady-state voltage with load of Figure 1B. This parameter is sampled and not 100% tested. At any given voltage and temperature, tkHOZ max is less than tkHOX1 min for a given device and from device to device.
- 6. This is a synchronous device. All addresses must meet the specified setup and hold times for ALL rising edges of clock (K) whenever TSP or TSC are low and the chip is selected. All other synchronous inputs must meet the specified setup and hold times for ALL rising edges of K when the chip is selected. Chip select must be true (S1 low and S0 high) at each rising edge of clock for the device (when TSP or TSC is low) to remain enabled. Timings for S1 and S0 are similar.

AC TEST LOADS



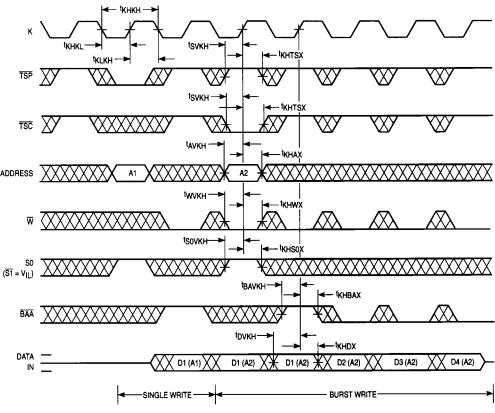
NOTE: For information on output I-V characteristics, see Chapter 8, Section 1.

READ-WRITE CYCLE



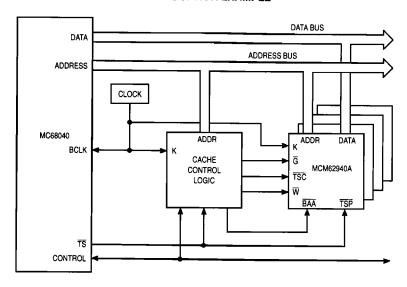
NOTE: Q1(A2) represents the first output from the external address A2; Q2(A2) represents the next output data in the burst sequence with A2 as the base address.

WRITE CYCLE



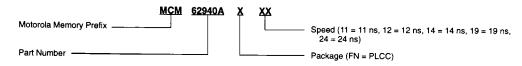
NOTE: $\overline{G} = V_{IH}$.

APPLICATION EXAMPLE



128K Byte Burstable, Secondary Cache Using Four MCM62940AFN24s with a 33 MHz MC68040

ORDERING INFORMATION (Order by Full Part Number)



Full Part Numbers — MCM62940AFN11 MCM62940AFN12 MCM62940AFN14 MCM62940AFN19 MCM62940AFN24